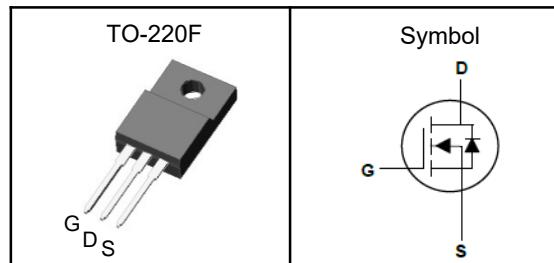


N-Channel Enhancement Mode MOSFET

Features

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant
- 100% UIS and Rg Tested

Pin Description



Applications

- Power Management in Desktop Computer
- DC/DC Converters

| | | |
|------------------|-----|------------------|
| V_{DSS} | 650 | V |
| $R_{DS(ON)-Typ}$ | 460 | $\text{m}\Omega$ |
| I_D | 16 | A |

Absolute Maximum Ratings ($T_J=25^\circ\text{C}$, Unless Otherwise Noted)

| Symbol | Parameter | Rating | Unit | |
|--------------|--|------------------------|------------------|---|
| V_{DSS} | Drain-Source Voltage | 650 | V | |
| V_{GSS} | Gate-Source Voltage | ± 30 | V | |
| T_J | Maximum Junction Temperature | -55 to 150 | $^\circ\text{C}$ | |
| T_{STG} | Storage Temperature Range | -55 to 150 | $^\circ\text{C}$ | |
| E_{AS} | Single Pulse Avalanche Energy ^③ | 698 | mJ | |
| $I_{DM}^{①}$ | Pulse Drain Current Tested | 64 | A | |
| I_D | Continuous Drain Current | $T_c=25^\circ\text{C}$ | 16 | A |
| P_D | Maximum Power Dissipation | $T_c=25^\circ\text{C}$ | 76 | W |

Thermal Characteristics

| Symbol | Parameter | Rating | Unit |
|-----------------|--|--------|---------------------------|
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient ₁ | 62.5 | $^\circ\text{C}/\text{W}$ |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case ₁ | 1.64 | $^\circ\text{C}/\text{W}$ |

Note ① : Max. current is limited by bonding wire.

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C .

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.

N-Channel Enhancement Mode MOSFET
Electrical Characteristics ($T_J=25^\circ\text{C}$, Unless Otherwise Noted)

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
|--|------------------------------------|--|-----|------|----------|------------------|
| Static Electrical Characteristics | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$ | 650 | --- | --- | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{\text{DS}}=650\text{V}$, $V_{\text{GS}}=0\text{V}$ | --- | --- | 1 | μA |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{\text{DS}}=V_{\text{GS}}$, $I_D=250\mu\text{A}$ | 3 | --- | 5 | V |
| I_{GSS} | Gate Leakage Current | $V_{\text{GS}}=\pm30\text{V}$, $V_{\text{DS}}=0\text{V}$ | --- | --- | ±100 | nA |
| $R_{\text{DS(ON)}}$ | Drain-Source On-state Resistance | $V_{\text{GS}}=10\text{V}$, $I_D=8\text{A}$ | --- | 460 | 520 | $\text{m}\Omega$ |
| Dynamic Characteristics^⑤ | | | | | | |
| C_{iss} | Input Capacitance | $V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=25\text{V}$, Freq.=1MHz | --- | 3325 | --- | pF |
| C_{oss} | Output Capacitance | | --- | 225 | --- | |
| C_{rss} | Reverse Transfer Capacitance | | --- | 22 | --- | |
| $T_{\text{d(on)}}$ | Turn-on Delay Time | $V_{\text{DD}}=325\text{V}$, $R_E=25\Omega$, $I_D=16\text{A}$ | --- | 175 | --- | nS |
| T_r | Turn-on Rise Time | | --- | 121 | --- | |
| $T_{\text{d(off)}}$ | Turn-off Delay Time | | --- | 373 | --- | |
| T_f | Turn-off Fall Time | | --- | 64 | --- | |
| Q_g | Total Gate Charge | $V_{\text{DS}}=520\text{V}$, $V_{\text{GS}}=10\text{V}$, $I_D=16\text{A}$ | --- | 50 | --- | nC |
| Q_{gs} | Gate-Source Charge | | --- | 20 | --- | |
| Q_{gd} | Gate-Drain Charge | | --- | 10 | --- | |
| Source-Drain Characteristics ($T_J=25^\circ\text{C}$) | | | | | | |
| V_{SD} | Diode Forward Voltage ^② | $V_{\text{GS}}=0\text{V}$, $I_S=16\text{A}$, $T_J=25^\circ\text{C}$ | --- | --- | 1.4 | V |
| t_{rr} | Reverse Recovery Time | $V_{\text{GS}}=0\text{V}$, $I_S=16\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$, $T_J=25^\circ\text{C}$ | --- | 484 | --- | nS |
| Q_{rr} | Reverse Recovery Charge | | --- | 1.62 | --- | nC |

Note ④ : Pulse test (pulse width $\leq300\mu\text{s}$, duty cycle $\leq2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

N-Channel Enhancement Mode MOSFET

Typical Characteristics

Fig. 1 Typical Output Characteristics

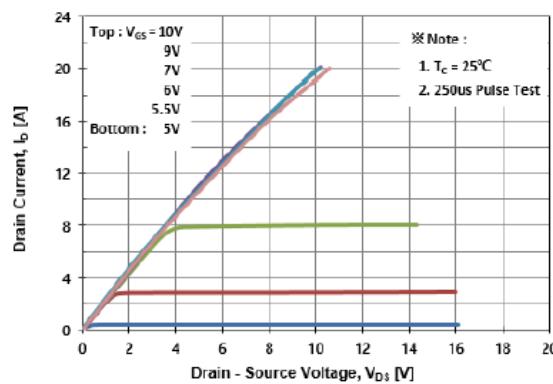


Fig. 2 Typical Output Characteristics

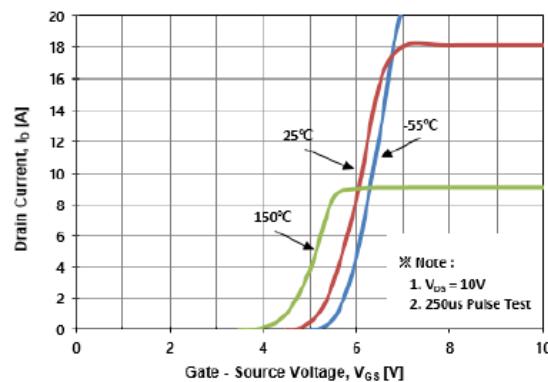


Fig. 3 On-Resistance Variation with Drain Current and Gate Voltage

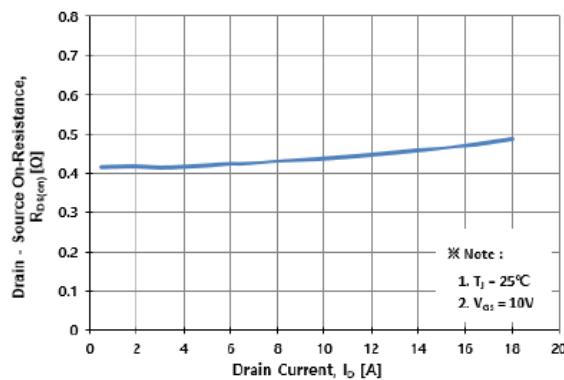


Fig. 4 Body Diode Forward Voltage Variation with Source Current

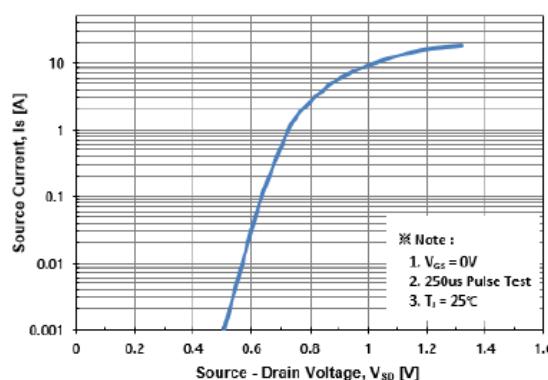


Fig. 5 Typical Capacitance Characteristics

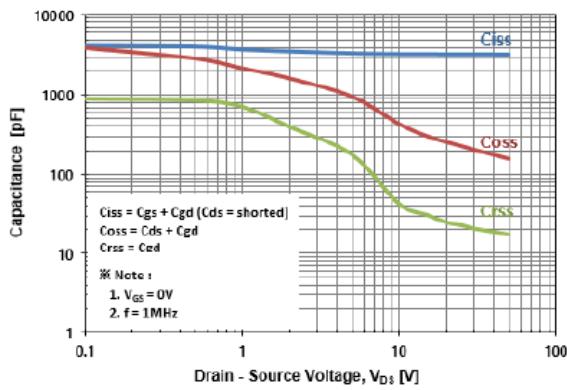
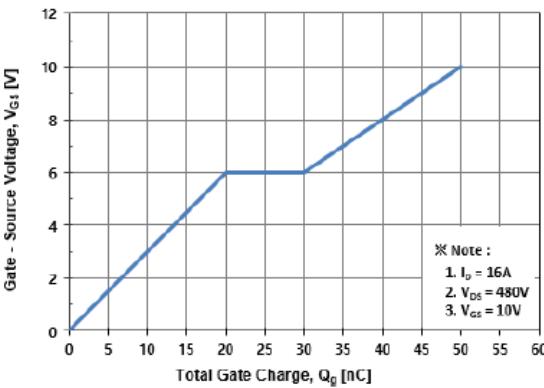


Fig. 6 Typical Total Gate Charge Characteristics



N-Channel Enhancement Mode MOSFET

Fig. 7 Breakdown Voltage Variation vs. Temperature

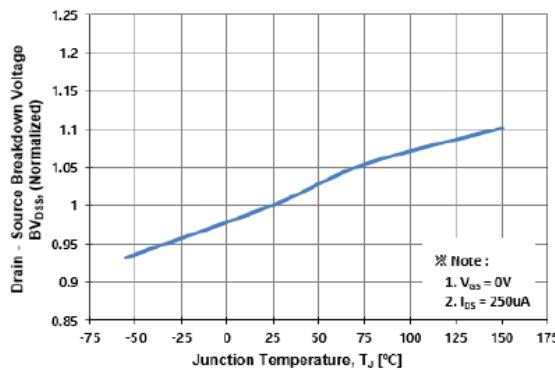


Fig. 8 On-Resistance Variation vs. Temperature

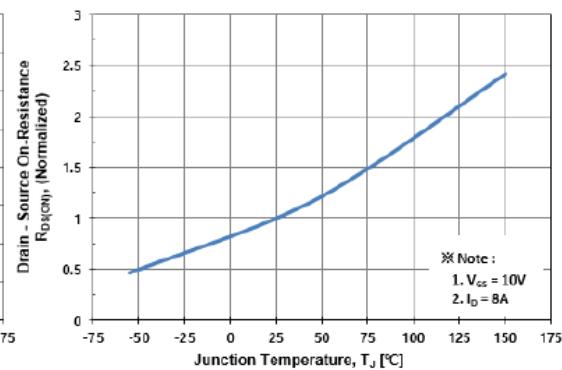


Fig. 9 Maximum Drain Current vs. Case Temperature

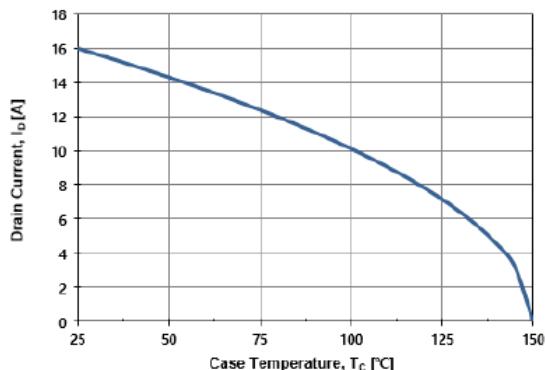


Fig. 10 Maximum Safe Operating Area

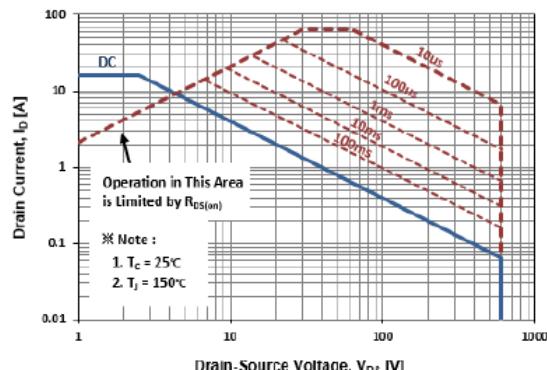
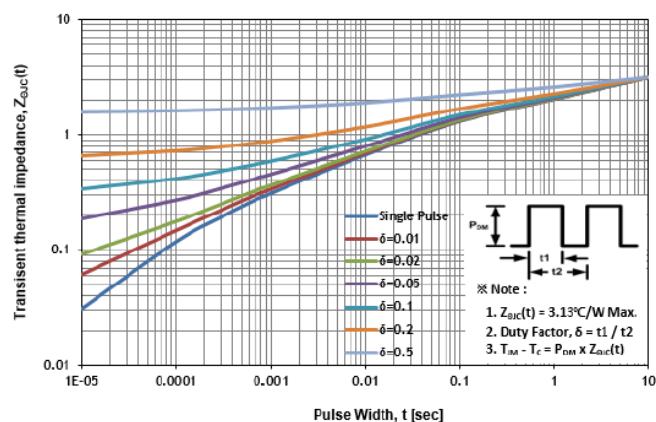


Fig. 11 Transient Thermal Impedance



N-Channel Enhancement Mode MOSFET

TO-220F Package Outline Data

